

CLAIMS

The claims are provided below for the convenience of the Examiner. The claims have not been amended.

1. (Previously Presented) An apparatus for socketing and testing integrates circuits comprising:

an air machine that is operable to controllably provide a thermally-varying air flow; and
a housing comprising (i) a printed circuit board that is operable to receive a device under test, and (ii) a controller that is operable to control testing of the received device under test;

wherein said air machine is associable with said housing to form an at least substantially air-tight chamber ensconcing the received device under test.

2. (Original) The apparatus as set forth in Claim 1 wherein said housing further comprises a power supply.

3. (Original) The apparatus as set forth in Claim 1 wherein said printed circuit board is circular shaped.

4. (Previously Presented) The apparatus as set forth in Claim 3 wherein said housing further comprises input/output (I/O) connectors that are placed circumferentially and symmetrically near the edge of the printed circuit board.

5. (Original) The apparatus as set forth in Claim 3 wherein said printed circuit board comprises a leadless socket.

6. (Original) The apparatus as set forth in Claim 5 wherein said leadless socket is operable to receive the device under test in the center of the Printed circuit board.

7. (Previously Presented) A method of operating an apparatus for socketing and testing integrated circuits, said apparatus comprising an air machine and a housing, said housing comprising a printed circuit board and a controller, said method comprising the steps of:

- (i) receiving a device under test, and
- (ii) associating said air machine with said housing to form an at least substantially air-tight chamber ensconcing the received device under test, the air machine operable to controllably provide a thermally-varying air flow.

8. (Original) The method as set forth in Claim 7 wherein said housing further comprises a power supply, and said method comprising the step of powering on the apparatus.

9. (Original) The method as set forth in Claim 7 wherein said printed circuit board is circular shaped, and said method comprising the step of controlling testing of the received device under test with said controller.

10. (Previously Presented) The method as set forth in Claim 9 wherein said housing further comprises input/output (I/O) connectors that are placed circumferentially and symmetrically near the edge of the printed circuit board.

11. (Original) The method as set forth in Claim 9 wherein said printed circuit board comprises a leadless socket.

12. (Original) The method as set forth in Claim 11 wherein said leadless socket is operable to receive the device under test in the center of the Printed circuit board.

13. (Previously Presented) An apparatus for socketing and testing integrated circuits comprising:

an air machine that is operable to controllably provide a thermally-varying air flow; and

a housing comprising (i) a universal printed circuit board that is operable to receive a device under test, (ii) a controller that is operable to control testing of the received device under test, and ~~(ii)~~ (iii) a power supply;

wherein said air machine is associable with said housing to form an at least substantially air-tight chamber ensconcing the received device under test.

14. (Original) The apparatus as set forth in Claim 13 wherein said power supply is a battery.

15. (Original) The apparatus as set forth in Claim 13 wherein said universal printed circuit board is circular shaped.

16. (Previously Presented) The apparatus as set forth in Claim 15 wherein said housing further comprises input/output (I/O) connectors that are placed circumferentially and symmetrically near the edge of the universal printed circuit board.

17. (Original) The apparatus as set forth in Claim 15 wherein said printed circuit board comprises a leadless socket.

18. (Original) The apparatus as set forth in Claim 17 wherein said leadless socket is operable to receive the device under test in the center of the printed circuit board.

19. (Previously Presented) The apparatus as set forth in Claim 13 wherein the device under test is one of a radio frequency (RF) integrated circuit and a high-frequency integrated circuit.

20. (Original) The apparatus as set forth in Claim 17 wherein said leadless socket is self-registering.